



YOUSHANG SEMICONDUCTOR

设计研发新型功率器件

各类小信号开关

中低压及高压大电流等场效应管

0755-83047638

ysbdt@szyoushang.cn

www.szyoushang.cn



企业微信二维码



企业QQ二维码

Product Summary

BV_{DSS}	R_{Ds(ON)} Max V_{GS} = 10V	I_D Max T_A = +25°C
100V	35mΩ	6.0A

Features and Benefits

- 100% Unclamped Inductive Switching (UIS) Test in Production – Ensures More Reliable and Robust End Application
- Low R_{Ds(ON)} – Ensures On-State Losses are Minimized
- Low Input Capacitance
- Fast Switching Speed
- Wettable Flank for Improved Optical Inspection

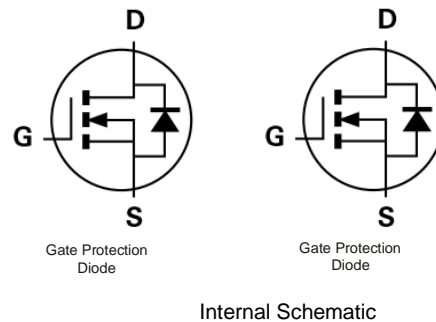
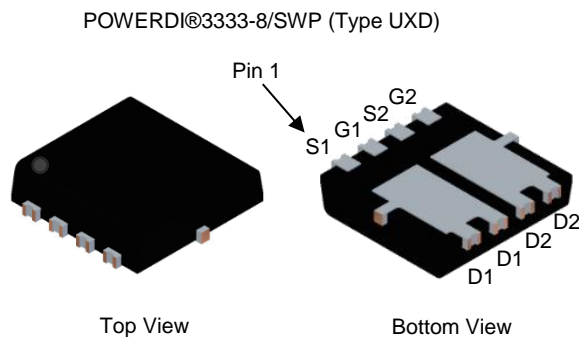
Description and Applications

This MOSFET is designed to meet the stringent requirements of automotive applications. It is qualified to AEC-Q101, supported by a PPAP and is ideal for use in:

- Wireless charging
- DC-DC converters
- Power managements

Mechanical Data

- Package: POWERDI[®]3333-8
- Package Material: Molded Plastic, “Green” Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See Diagram
- Terminals: Finish — Matte Tin Annealed over Copper Leadframe. Solderable per MIL-STD-202, Method 208
- Weight: 0.03 grams (Approximate)



Maximum Ratings (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			V_{DS}	100	V
Gate-Source Voltage			V_{GS}	± 20	V
Continuous Drain Current, $V_{GS} = 10\text{V}$ (Note 5)	Steady State	$T_A = +25^\circ\text{C}$	I_D	6.0	A
		$T_A = +70^\circ\text{C}$		4.8	
Pulsed Drain Current (10 μs Pulse, Duty Cycle = 1%)			I_{DM}	35	A
Maximum Continuous Body Diode Forward Current (Note 5)			I_S	2.2	A
Pulsed Body Diode Forward Current (10 μs Pulse, Duty Cycle = 1%)			I_{SM}	35	A
Avalanche Current, $L = 0.3\text{mH}$			I_{AS}	13	A
Avalanche Energy, $L = 0.3\text{mH}$			E_{AS}	25.3	mJ

Thermal Characteristics (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic		Symbol	Value	Unit
Total Power Dissipation (Note 6)	$T_A = +25^\circ\text{C}$	P_D	1.2	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	$R_{\theta JA}$	107	$^\circ\text{C/W}$
Total Power Dissipation (Note 5)	$T_A = +25^\circ\text{C}$	P_D	2.3	W
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	$R_{\theta JA}$	55	$^\circ\text{C/W}$
Thermal Resistance, Junction to Case (Note 5)		$R_{\theta JC}$	5.5	$^\circ\text{C/W}$
Operating and Storage Temperature Range		T_J, T_{STG}	-55 to +150	$^\circ\text{C}$

Electrical Characteristics (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV_{DS}	100	—	—	V	$V_{GS} = 0\text{V}, I_D = 1\text{mA}$
Zero Gate Voltage Drain Current	I_{DSS}	—	—	1	μA	$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}$
Gate-Source Leakage	I_{GSS}	—	—	± 100	nA	$V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	$V_{GS(TH)}$	2	—	4	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
Static Drain-Source On-Resistance	$R_{DS(ON)}$	—	27	35	m Ω	$V_{GS} = 10\text{V}, I_D = 5\text{A}$
Diode Forward Voltage	V_{SD}	—	0.8	1.0	V	$V_{GS} = 0\text{V}, I_S = 5\text{A}$
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	C_{iss}	—	544	—	pF	$V_{DS} = 50\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$
Output Capacitance	C_{oss}	—	181	—	pF	
Reverse Transfer Capacitance	C_{rss}	—	6.0	—	pF	
Gate Resistance	R_g	—	1.2	—	Ω	$V_{DS} = 0\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$
Total Gate Charge ($V_{GS} = 4.5\text{V}$)	Q_g	—	4.3	—	nC	$V_{DS} = 50\text{V}, I_D = 7\text{A}$
Total Gate Charge ($V_{GS} = 10\text{V}$)	Q_g	—	8.0	—	nC	
Gate-Source Charge	Q_{gs}	—	1.8	—	nC	
Gate-Drain Charge	Q_{gd}	—	2.4	—	nC	
Turn-On Delay Time	$t_{D(ON)}$	—	8.5	—	ns	$V_{DS} = 50\text{V}, I_D = 7\text{A}$ $V_{GS} = 10\text{V}, R_{GEN} = 6\Omega$
Turn-On Rise Time	t_R	—	2.7	—	ns	
Turn-Off Delay Time	$t_{D(OFF)}$	—	11.9	—	ns	
Turn-Off Fall Time	t_F	—	6.2	—	ns	$I_F = 7\text{A}, di/dt = 100\text{A}/\mu\text{s}$
Reverse Recovery Time	t_{RR}	—	33.2	—	ns	
Reverse Recovery Charge	Q_{RR}	—	34.3	—	nC	

- Notes:
5. Device mounted on FR-4 substrate PCB, 2oz copper, with thermal bias to bottom layer 1 inch square copper plate.
 6. Device mounted on FR-4 PCB, with minimum recommended pad layout.
 7. Short duration pulse test used to minimize self-heating effect.
 8. Guaranteed by design. Not subject to product testing.

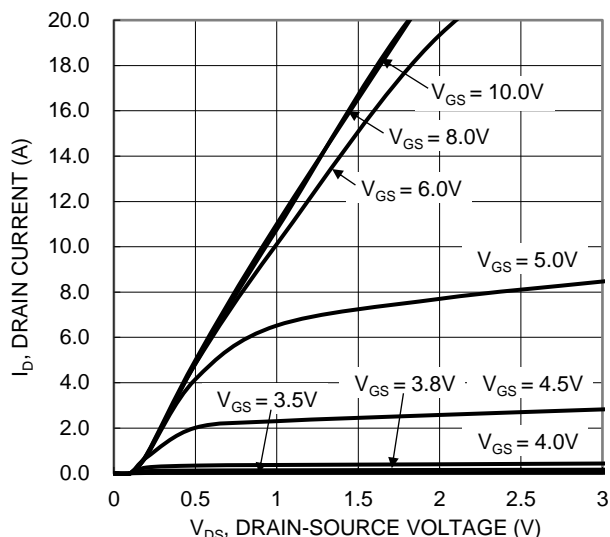


Figure 1. Typical Output Characteristic

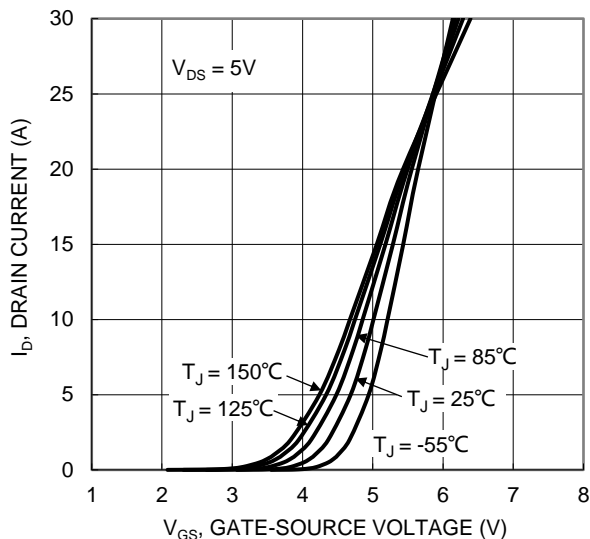


Figure 2. Typical Transfer Characteristic

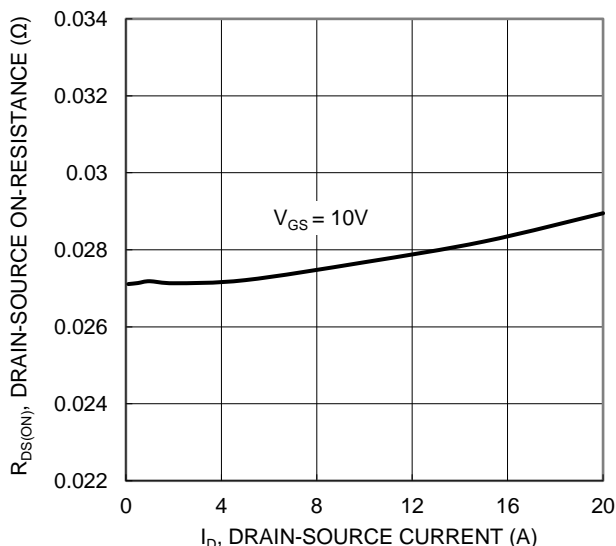


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

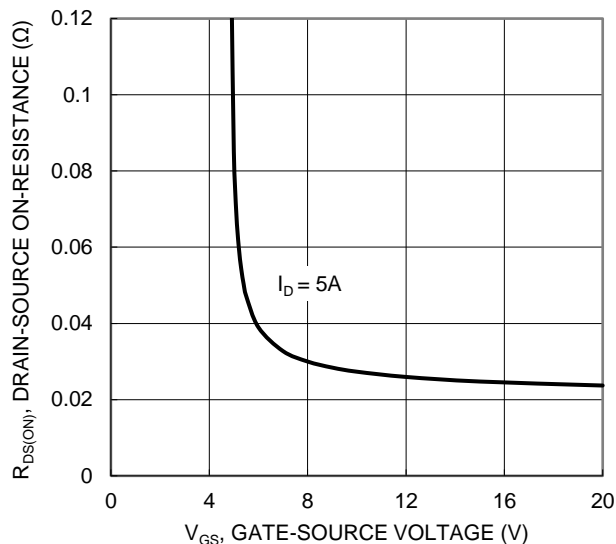


Figure 4. Typical Transfer Characteristic

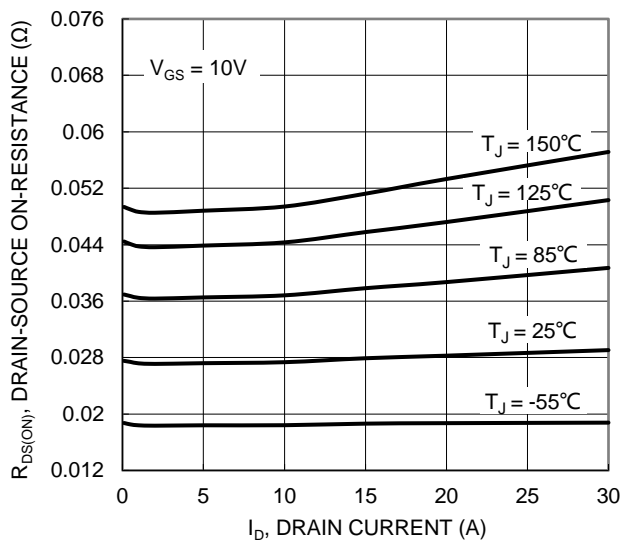


Figure 5. Typical On-Resistance vs. Drain Current and Junction Temperature

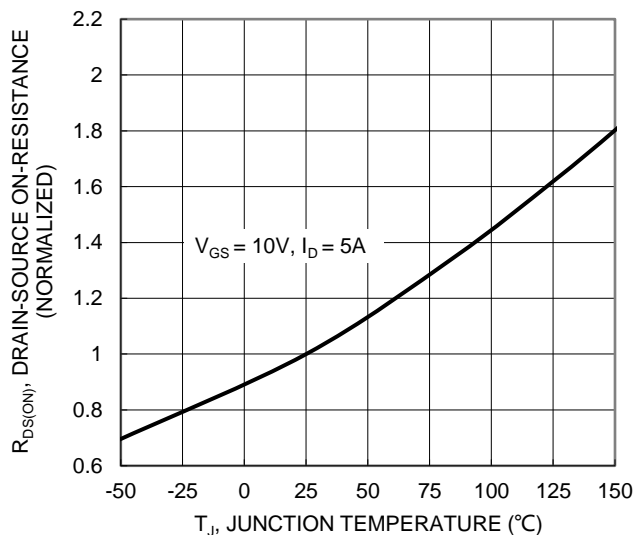
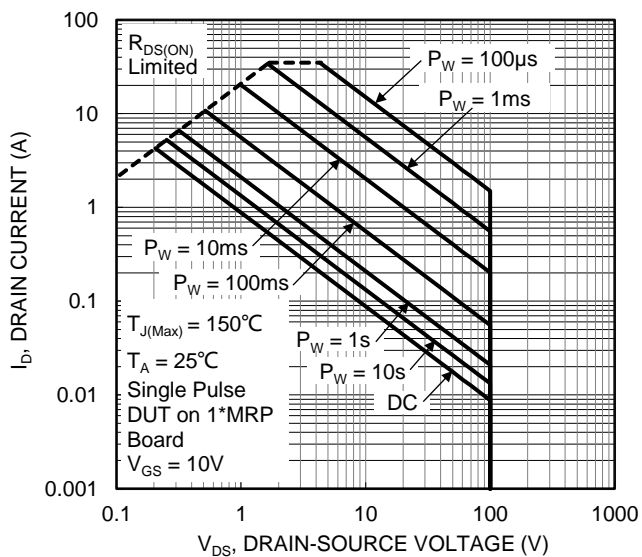
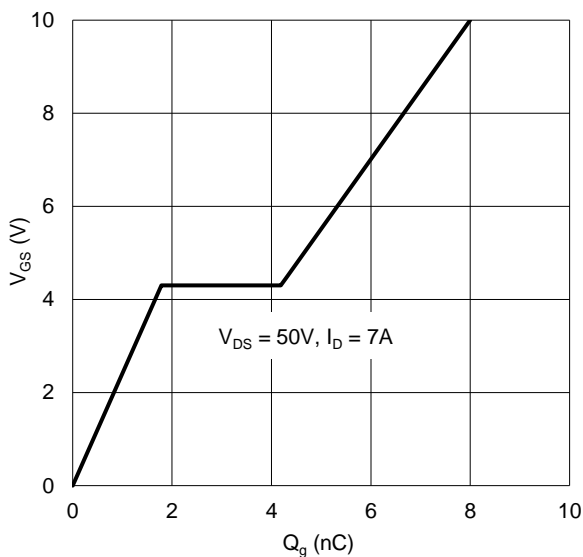
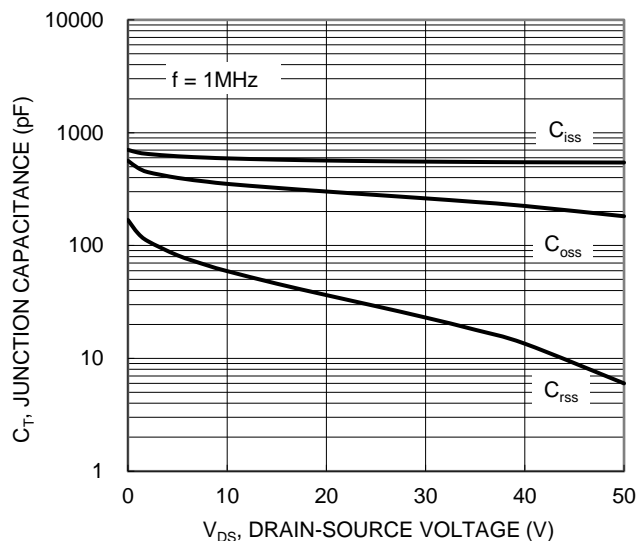
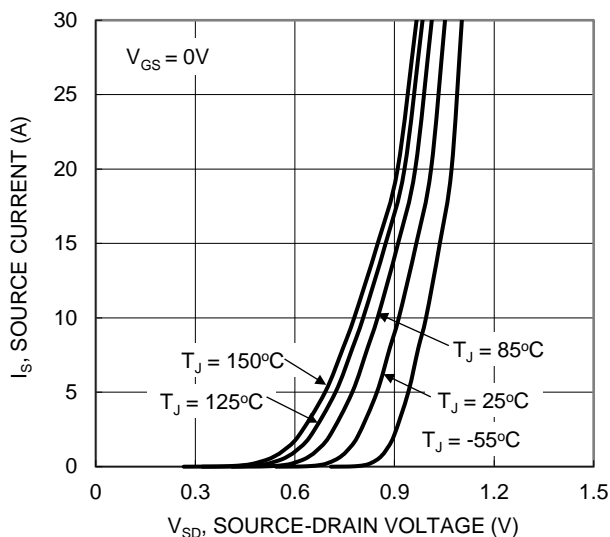
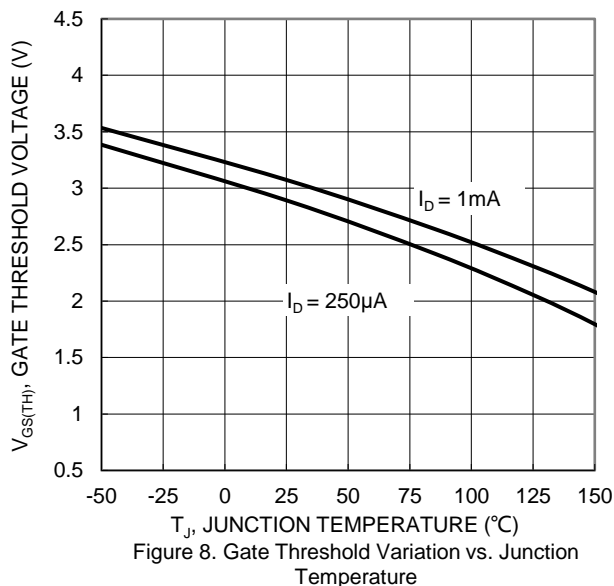
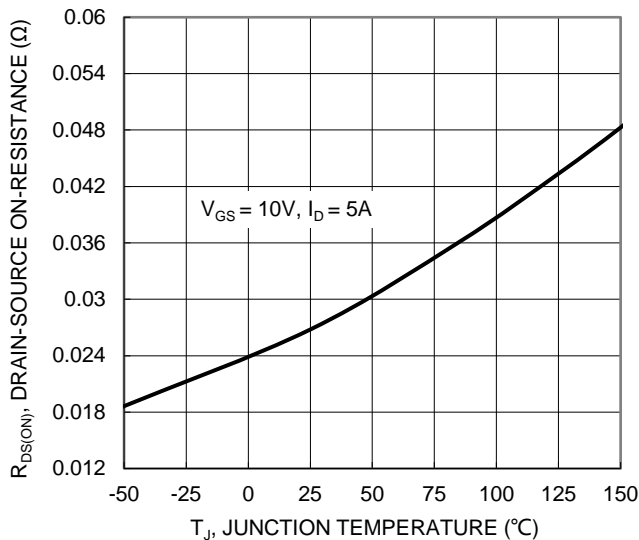


Figure 6. On-Resistance Variation with Temperature



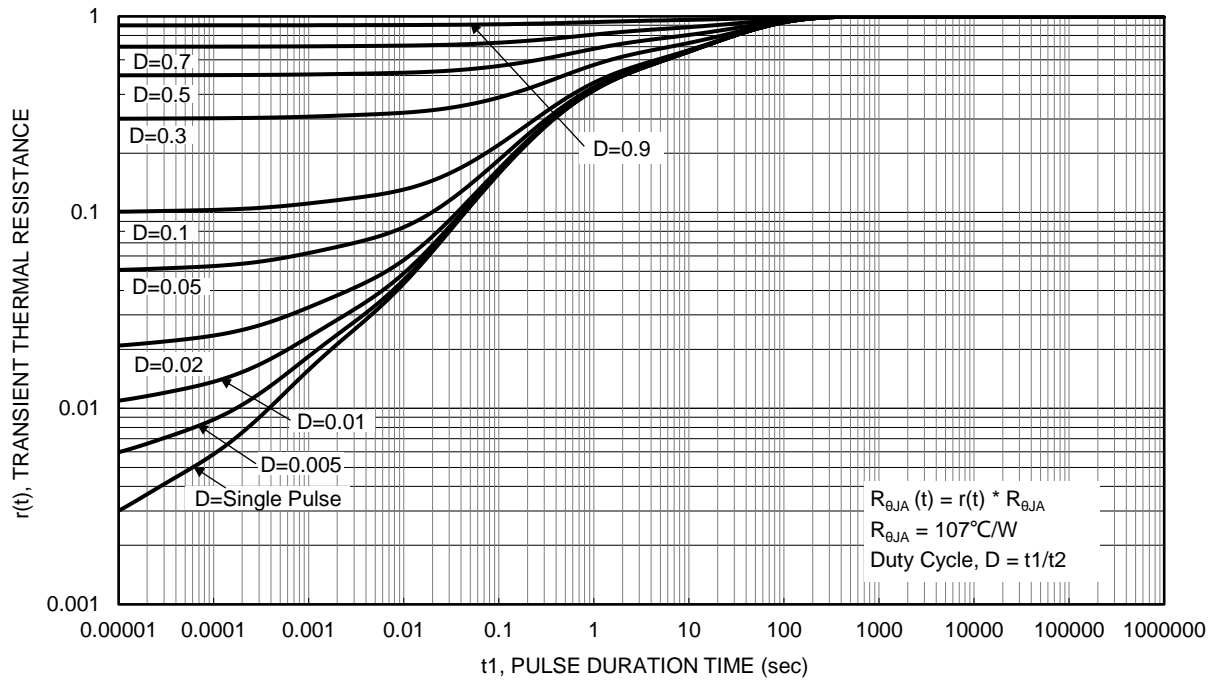
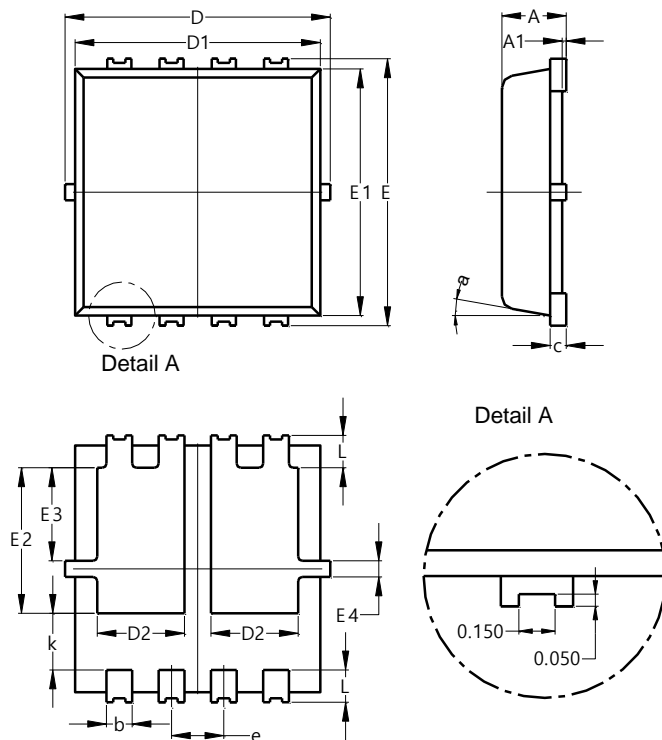


Figure 13. Transient Thermal Resistance

Package Outline Dimensions

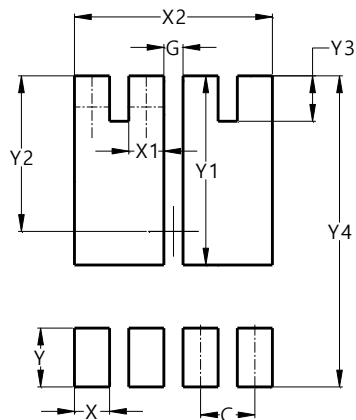
POWERDI[®]3333-8/SWP (Type UXD)



POWERDI [®] 3333-8/SWP (Type UXD)			
Dim	Min	Max	Typ
A	0.75	0.85	0.80
A1	0.00	0.05	—
b	0.25	0.40	0.32
c	0.10	0.25	0.15
D	3.20	3.40	3.30
D1	2.95	3.15	3.05
D2	1.00	1.20	1.10
E	3.20	3.40	3.30
E1	2.95	3.15	3.05
E2	1.60	2.00	1.80
E3	0.95	1.35	1.15
E4	0.10	0.30	0.20
e	—	—	0.65
L	0.30	0.50	0.40
k	0.50	0.90	0.70
a	0°	12°	10°
All Dimensions in mm			

Suggested Pad Layout

POWERDI[®]3333-8/SWP (Type UXD)



Dimensions	Value (in mm)
C	0.650
G	0.230
X	0.420
X1	0.420
X2	2.370
Y	0.700
Y1	2.250
Y2	1.850
Y3	0.540
Y4	3.700